



**AAEON**Technology INC.  
ISO-9001/ISO-14001 Certified  
Industrial Automation PCs

**GENE-6310**  
Dynamic Test  
**Temperature / Humidity Test Report**

Issued by:

\_\_\_\_\_  
Rex Chang  
QE Engineer

/

*04/02/2002*

\_\_\_\_\_  
Date

Reviewed by:

\_\_\_\_\_  
Wen - Yuan Yang  
QE Manager

/

*04/02/2002*

\_\_\_\_\_  
Date

1. Test Product: VIA Low-power SubCompact Board

2. Model Name: GENE-6310 REV.A0.3

3. Test Date: 03-25-2002

4. Test Site: AAEON QA Internal Lab.

5. Test Equipment

Type	MFR	Model Number	Serial Number	Last CAL.
Programmable Temperature & Humidity Chamber	KSON	Ths-D4L+-100	2582	10/29/01

6. Test Standard :

NO.	Description
IEC 68-2-61	Test Z/ABD : Climatic Sequence Test

7. Testing Item:

Temperature & Humidity Cycle

8. Additional Test Peripheral:

Configuration	Model
Test Software	<u>QAPlus 5.5</u>

9. Test Environment:

Temperature: 20 ± 2

Humidity: 60 ± 20%RH

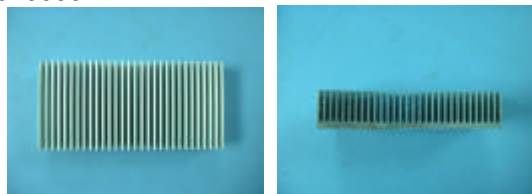
10. Sample Configuration & Quantity Under Test:

Quantity: 1

Sample Configuration:

CPU	Onboard VIA C3 Eden EPGA Mobile CPU 667MHz (133 FSB)
DRAM	SO-DIMM 512MB HITACHI HB52RF648DC-75B (PC-133 SDRAM)
System BIOS Version	GENE-6310 BIOS Rev.0.8
Chipset	VT8606 (66/100/133 FSB) / VT82C686B
VGA Chipset	North Bridge VT8606 (Share memory up to 32MB)
I/O Chipset	VT82C686B
Heat sink (P/N)	M166310000

Heat sink (P/N): M166310000



11. Test Result:

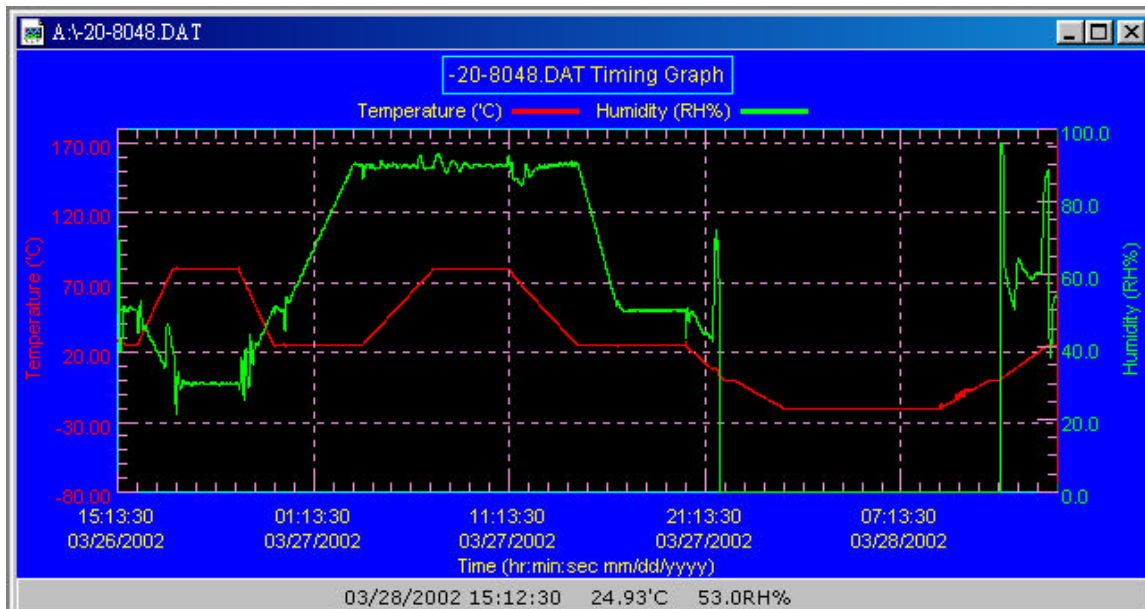
Standard	Description	Result
IEC 68-2-61	Temperature & Humidity Cycle Test (Run QAPlus 5.5)	Pass

12. Temperature & Humidity Cycle Test:

12-1 Testing Specification:

Step	Temperature ( )	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	80	30	01:50
4	80	30	03:20
5	25	50	01:50
6	25	50	00:30
7	25	90	03:30
8	25	90	00:30
9	80	90	03:40
10	80	90	03:40
11	25	90	03:40
12	25	50	02:00
13	25	50	03:00
14	25	50	00:30
15	0	0	02:00
16	0	0	00:30
17	-20	0	02:30
18	-20	0	08:00
19	0	0	02:30
20	0	0	00:30
21	25	50	02:30
22	25	50	00:30

12-2 Test Curve:





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Industrial Automation PCs

**GENE-6310**  
Power On/Off Test  
**Temperature / Humidity Test Report**

Issued by:	_____ / _____
	<b>Rex Chang</b> QE Engineer
	<b>04/02/2002</b> Date
Reviewed by:	_____ / _____
	<b>Wen - Yuan Yang</b> QE Manager
	<b>04/02/2002</b> Date

1. Test Product: VIA Low-power SubCompact Board

2. Model Name: GENE-6310 REV.A0.3

3. Test Date: 03-25-2002

4. Test Site: AAEON QA Internal Lab.

5. Test Equipment

Type	MFR	Model Number	Serial Number	Last CAL.
Programmable Temperature & Humidity Chamber	KSON	Ths-D4L+-100	2582	10/29/01

6. Test Standard :

NO.	Description
IEC 68-2-30	Test DB : Damp Heat Test

7. Testing Item:

Test Temperature & Humidity Power On/Off Test

8. Additional Test Peripheral:

Configuration	Model
Test Fixture	Power on/off(110V) Fixture

9. Test Environment:

Temperature: 20 ± 2

Humidity: 60 ± 20%RH

10. Sample Configuration & Quantity Under Test:

Quantity: 2

Sample Configuration:

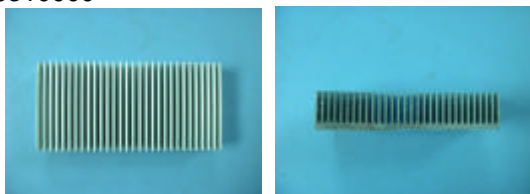
10-1 Sample 1

CPU	Onboard VIA C3 Eden EBG Mobile CPU 667MHz (133 FSB)
DRAM	SO-DIMM 64MB NEC D45128163G5-A75-9JF (PC-133 SDRAM)
System BIOS Version	GENE-6310 BIOS Rev.0.8
Chipset	VT8606 (66/100/133 FSB) / VT82C686B
VGA Chipset	North Bridge VT8606 (Share memory up to 32MB)
I/O Chipset	VT82C686B
Heat sink (P/N)	M166310000

10-2 Sample 2

CPU	Onboard VIA C3 Eden EBG Mobile CPU 533 MHz (133 FSB)
DRAM	SO-DIMM 64MB KINGMAX KSV684T4A2A-07L (PC-133 SDRAM)
System BIOS Version	GENE-6310 BIOS Rev.0.8
Chipset	VT8606 (66/100/133 FSB) / VT82C686B
VGA Chipset	North Bridge VT8606 (Share memory up to 32MB)
I/O Chipset	VT82C686B
Heat sink (P/N)	M166310000

Heat sink (P/N): M166310000



11. Test Result:

Standard	Description	Result
IEC 68-2-30	Temperature & Humidity Power On/Off Test	Pass

12. Temperature & Humidity Power On/Off Test  
 12-1 Testing Specification:

Step	Temperature ( )	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

12-2 Test Curve:

